## Notice of References Cited

Application/Control No. 10/605,255	Reexamination	Applicant(s)/Patent Under Reexamination CHEN ET AL.		
Examiner	Art Unit			
Binh X Tran	1765		Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,713,834	03-2004	Mori et al.	257/510
	В	US-6,818,508	11-2004	Shimizu et al.	438/257
	C	US-6,797,565	09-2004	Yang et al.	438/261
	D	US-6,791,142	09-2004	Tseng, Horng-Huei	257/316
	Ε	US-6,689,658	02-2004	Wu, Ching-Yuan	438/257
	F	US-6,462,372	10-2002	Wu, Ching-Yuan	257/314
	G	US-6,406,961	06-2002	Chen, Bin-Shing	438/266
	н	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Ъ					
	Ø					
	R			•		
	S	·				
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	V					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.